Triacs BTA140 series

GENERAL DESCRIPTION

Passivated triacs in a plastic envelope, intended for use in applications requiring high bidirectional transient and blocking voltage capability and high thermal cycling performance. Typical applications include motor control, industrial and domestic lighting, heating and static switching.

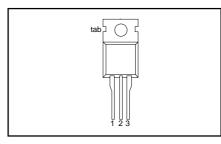
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT	
	BTA140- Repetitive peak off-state	600	800		
V_{DRM}	voltages	600	800	V	
I _{T(RMS)} I _{TSM}	RMS on-state current Non-repetitive peak on-state current	25 190	25 190	A A	

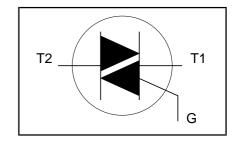
PINNING - TO220AB

PIN	DESCRIPTION		
1	main terminal 1		
2	main terminal 2		
3	gate		
tab	main terminal 2		

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		MAX.		UNIT
V _{DRM}	Repetitive peak off-state voltages		-	-600 600 ¹	-800 800	V		
I _{T(RMS)} I _{TSM}	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{mb} \le 91 ^{\circ}C$ full sine wave; $T_{j} = 25 ^{\circ}C$ prior to surge	-	25		A		
		t = 20 ms	-		90	A		
124	124 for fronting	t = 16.7 ms	-	209		A A ² s		
l²t dl _⊤ /dt	l ² t for fusing Repetitive rate of rise of on-state current after	t = 10 ms $I_{TM} = 30 \text{ A}; I_G = 0.2 \text{ A};$ $dI_G/dt = 0.2 \text{ A}/\mu\text{s}$	-	18	30	A-S		
	triggering	T2+ G+	-		0	A/μs		
		T2+ G-	-		0	A/μs		
		T2- G- T2- G+	-		0 0	A/μs		
1	Peak gate current	12- 9+	[',	2	A/μs Å		
I _{GM} P _{GM}	Peak gate power		_	1	<u>2</u> 5	W		
P _{G(AV)}	Average gate power	over any 20 ms period	-		.5	l w		
T _{stg}	Storage temperature Operating junction temperature		-40 -		50 25	,C		

¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15 $A/\mu s$.

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THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-mb}	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle in free air		- - 60	1.0 1.4 -	K/W K/W K/W

STATIC CHARACTERISTICS

T_i = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP.	MAX.	UNIT
I _{GT}	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$					
01			T2+ G+	-	6	35	mA
			T2+ G-	-	10	35	mΑ
			T2- G-	-	11	35	mA
			T2- G+	-	23	70	mA
I _L	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$					
			T2+ G+	-	8	40	mA
			T2+ G-	-	30	60	mA
			T2- G-	-	18	40	mΑ
			T2- G+	-	15	60	mA
I _H	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$					
			<u>T</u> 2+	-	7	30	mA
			T2-	-	12	30	mΑ
V_T	On-state voltage	$I_{T} = 30 \text{ A}$		-	1.3	1.55	V
V_{GT}	Gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$	- 0.0		0.7	1.5	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_L = 125$	5 °C	0.25	0.4		V
I_D	Off-state leakage current	$V_D = V_{DRM(max)}$; $T_j = 125 °C$		-	0.1	0.5	mA

DYNAMIC CHARACTERISTICS

 $T_i = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV _D /dt	Critical rate of rise of	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125 °C;$	100	300	-	V/μs
dV _{com} /dt	off-state voltage Critical rate of change of commutating voltage	exponential waveform; gate open circuit $V_{DM} = 400 \text{ V}$; $T_j = 95 ^{\circ}\text{C}$; $I_{T(RMS)} = 25 \text{ A}$; $I_{Com}/\text{dt} = 9 \text{ A/ms}$; gate open circuit	-	10	-	V/μs
t _{gt}	Gate controlled turn-on time	$I_{TM} = 30 \text{ A}; V_D = V_{DRM(max)}; I_G = 0.1 \text{ A};$ $I_{G} = 5 \text{ A}/\mu \text{s}$	-	2	-	μs

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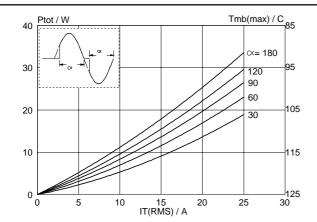


Fig.1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_{T(RMS)}$, where $\alpha =$ conduction angle.

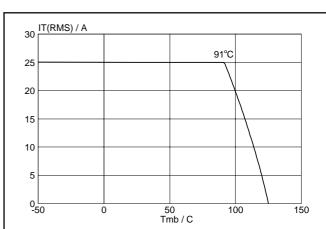


Fig.4. Maximum permissible rms current $I_{T(RMS)}$, versus mounting base temperature T_{mb} .

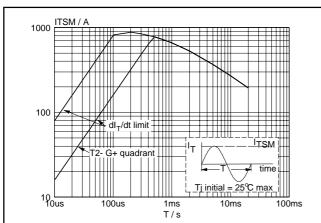


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \le 20$ ms.

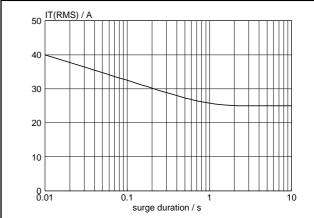


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{mb} \le 91$ °C.

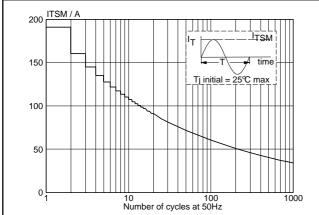


Fig.3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, f = 50 Hz.

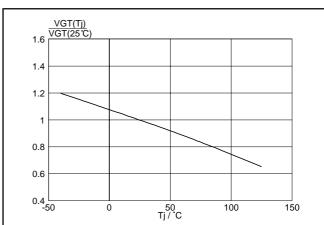
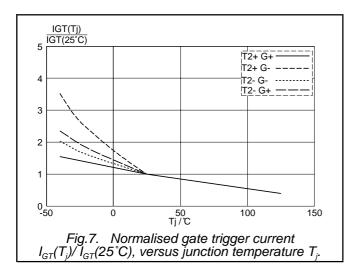


Fig.6. Normalised gate trigger voltage $V_{GT}(T_i)/V_{GT}(25^{\circ}C)$, versus junction temperature T_i .

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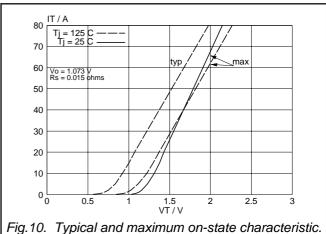
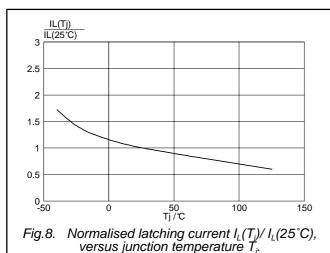


Fig. 10. Typical and maximum on-state characteristic.



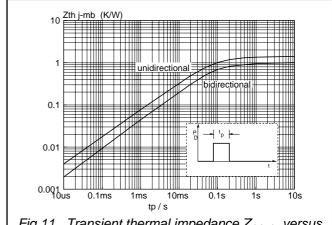


Fig.11. Transient thermal impedance $Z_{th j-mb}$, versus pulse width $t_{\rm p}$

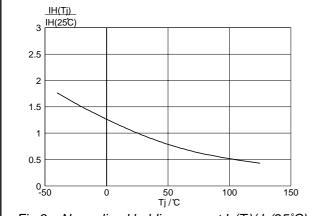


Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}\text{C})$, versus junction temperature T_j .

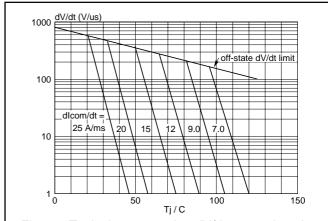
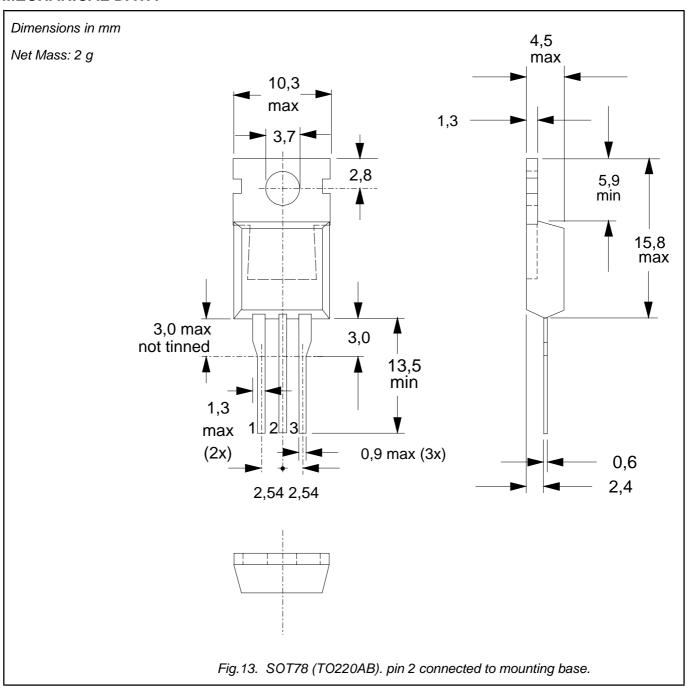


Fig.12. Typical commutation dV/dt versus junction temperature, parameter commutation dl_T/dt. The triac should commutate when the dV/dt is below the value on the appropriate curve for pre-commutation dI_{τ}/dt .

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MECHANICAL DATA



- Notes
 1. Refer to mounting instructions for SOT78 (TO220) envelopes.
 2. Epoxy meets UL94 V0 at 1/8".

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DEFINITIONS

DATA SHEET STATUS					
DATA SHEET STATUS ²	PRODUCT STATUS ³	DEFINITIONS			
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice			
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product			
Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Changes will be communicated according to the Customer Product/Process Change Notification (CPCN) procedure SNW-SQ-650A			

Limiting values

Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

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² Please consult the most recently issued datasheet before initiating or completing a design.

³ The product status of the device(s) described in this datasheet may have changed since this datasheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.